

Out of Stock - Item is not available at this time - Overlay wafer standard

Art. ID	NIST-5000
Unit	each
Deliverydetails	No Dangerous Good /not restricted

Description

This Standard Reference Material (SRM®) is a 200 mm double-etched silicon wafer containing calibrated overlay targets. NIST-5000 is intended primarily for calibrating optical microscopes used to make overlay (OL) measurements. It is also useful in calibrating other types of instruments capable of making overlay measurements, such as scanning electron microscopes or atomic force microscopes, provided that they have an appropriate level of magnification and have the proper sample-holding capabilities.

Text/Information	Analyte/Parameter	CAS number	Concentration/Value	Unit	Method	Source
OL Value (nm)	XN100		-122,44	nm		
OL Value (nm)	XN030		-55,86	nm		
OL Value (nm)	XP000		-29,66	nm		
OL Value (nm)	XP030		-0,53	nm		
OL Value (nm)	XP100		72,5	nm		
OL Value (nm)	YN050		-39,13	nm		
OL Value (nm)	YN010		3,16	nm		
OL Value (nm)	YP000		13,88	nm		
OL Value (nm)	YP010		23,44	nm		
OL Value (nm)	YP05		64,51	nm		